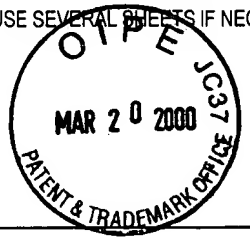
FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)



ATTY. DOCKET NO.	APPLICATION NO.
FILLF1.0001CP1	09/460,630
APPLICANT: Dierickx	
FILING DATE: DECEMBER 14, 1999	GROUP: 2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
EL		4,473,836	9/25/84	Chamberlain			
EL		4,565,756	1/21/86	Needs et al.			
EL		4,580,103	4/1/86	Tompsett			
EL		4,647,975	3/3/87	Alston et al.			
EL		5,146,074	9/8/92	Kawahara et al.			
EL		5,153,420	10/6/92	Hack et al.			
EL		5,164,832	11/17/92	Halvis et al.			
EL		5,258,845	11/2/93	Kyuma et al.			
EL		5,296,696	3/22/94	Uno			
EL		5,321,528	6/14/94	Nakamura			
EL		5,335,008	8/2/94	Hamasaki			
EL		5,608,204	3/4/97	Hofflinger et al.			
EL		5,614,744	3/25/97	Merrill			
EL		5,841,126	11/24/98	Fossum			
EL		5,898,196	4/27/99	Hook et al.			
EL		5,101,253	3/31/92	Mizutani et al.			
EL		5,903,021	5/11/99	Lee et al.			
EL		5,625,210	4/29/97	Leet et al.			
EL		5,904,493	5/18/99	Lee et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
EL		548 987	6/30/93	Europe				
EL		657 863	6/14/95	Europe				
EL		739 039	10/23/96	Europe				
EL		93/19489	9/30/93	PCT				
EL		2324651	28/10/98	Great Britian				

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EXAMINER INITIAL		**OTHER DOCUMENTS** (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
EL		Aoki et al., "A Collinear 3-Chip Image Sensor", IEEE International Solid-State Circuits Conference, 1985, pp. 102-103.
EL		Horii et al., "A 490 x 404 Element Imager for a Single-Chip Color Camera", IEEE International Solid-State Circuits Conference, 1985, pp. 96-97.
EL		Nagakawa et al., "A 580 x 500-Element CCD Imager with a Shallow Flat P Well", IEEE International Solid-State Circuits Conference, 1985, pp.98-99.
EL		Mahowald, M.A., "Silicon Retina with Adaptive Photoreceptors", SPIE, Vol. 1473, 1991, pp. 52-58.
EL		Mann, J. "Implementing Early Visual Processing In Analog VLSI: Light Adaptation", SPIE, Vol 1473, 1991, pp. 128-136.
EL		Ono et al., "Analysis of Smear Noise In Interline-CCD Image Sensor with Gate-Free Isolation Structure", Abstract of the 1991 Int'l Conference on Solid State Devices and Materials, Yokohama, 1991, pp. 68-70.
EL		Yadid-Pecht et al., "A Random Access Photodiode Array for Intelligent Image Capture", IEEE Transactions on Electron Devices, Vol. 38, No. 8 August 1991.
EL		Ricquier et al., "Pixel Structure with Logarithmic Response for Intelligent and Flexible Imager Architectures", Microelectronic Engineering, 19 (1992), pp. 631-634
EL		Sevenhans, et al., "A 400mm Long Linear X-Ray Sensitive Image Sensor", IEEE International Solid-State Circuits Conference, 1987, pp. 108-109.
EL		Anderson, S. et al., "A Single Chip Sensor & Image Processor or Fingerprint Verification", IEEE 1991 Custom Integrated Circuits Conference, May 12-15, 1991, pp. 12.1.1-12.1.4.
EL		Dierickx, Bart, "XYW Detector: A Smart Two-Dimensional Particle Sensor", Nuclear Instruments and Mthods in Physics Research A275, North-Holland Physics Publisihing Division, 1989, pp. 542-544.
EL	-	Klein, P., "Design and Performance of Semiconductor Detectors with Integrated Amplification and Charge Storage Capability", Nuclear Instruments and Methods in Physics Research A305, 1991, pp. 517-526.
EL		Aw, Chye Huat, et al., "A 128 x 128-Pixel Standard-CMOS Image Sensor with Electronic Shutter", IEEE Journal of Solid State Circuits, Vol.31, No. 12, December 1996, pp. 1922-1930.
EL		Martin, W.J. et al., "Dynamic Offset Null", IBM Technical Disclosure Bulletin, No. 23, No. 9, February 1981, pp. 4195-4196.

EXAMINER	DATE CONSIDERED 5/10/01

***EXAMINER**: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.